

Page 2 of 2							
FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT	<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 50%;">ATTY. DOCKET NO. 1857.1460001</td> <td style="width: 50%;">APPLICATION NO. 10/786,361</td> </tr> <tr> <td colspan="2">FIRST NAMED INVENTOR Matthew E. Hansen</td> </tr> <tr> <td>FILING DATE February 26, 2004</td> <td>ART UNIT 2877</td> </tr> </table>	ATTY. DOCKET NO. 1857.1460001	APPLICATION NO. 10/786,361	FIRST NAMED INVENTOR Matthew E. Hansen		FILING DATE February 26, 2004	ART UNIT 2877
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FIRST NAMED INVENTOR Matthew E. Hansen							
FILING DATE February 26, 2004	ART UNIT 2877						

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA2						
	AB2						
	AC2						
	AD2						
	AE2						
	AF2						
	AG2						
	AH2						
	AI2						
	AJ2						
	AK2						

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AL2						Yes
	AM2						No
	AN2						Yes
	AO2						No
	AP2						Yes
							No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
<i>sk</i>	AR	2	Copy of European Search Report for European Appln. 00112970.9 mailed April 14, 2004.
<i>sk</i>	AS	2	J.P. Kirk and C.J. Proglar, "Application of Blazed Gratings for Determination of Equivalent Primary Azimuthal Aberrations", March 1999, Optical Microlithography XII, vol. 3679, pp. 70-76.
	AT	2	

EXAMINER	DATE CONSIDERED <i>1/29/06</i>
EXAMINER'S Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.	

FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO.
1857.1460001APPLICATION NO.
10/786,361FIRST NAMED INVENTOR
Matthew E. HansenFILING DATE
February 26, 2004ART UNIT
2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA1						
	AB1						
	AC1						
	AD1	4,289,959	09/15/1981	Takayama <i>et al.</i>			
	AE1	5,814,425	09/29/1998	Kataoka <i>et al.</i>			
	AF1	2002-0021460A1	02/21/2002	Hansen			
	AG1	2004-0001192A1	01/01/2004	Lyons <i>et al.</i>			
	AH1						
	AI1						
	AJ1						
	AK1						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AL1						Yes No
	AM1						Yes No
all	AN1	EP 0 628 806 A2	04/28/1994	Europe	—	—	Yes No
	AO1					—	Yes No
	AP1						Yes No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	1	
	AS	1	
	AT	1	

EXAMINER

DATE CONSIDERED

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